

<b>Notice of References Cited</b>		Application/Control No. 10/583,593	Applicant(s)/Patent Under Reexamination LEE ET AL.	
		Examiner LEON-VIET Q. NGUYEN	Art Unit 2611	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0072678 A1	04-2006	Hadad, Zion	375/260
*	B	US-7,397,838 B2	07-2008	Laroia et al.	375/132
*	C	US-7,418,039 B2	08-2008	Simmonds, Christopher Martin	375/260
*	D	US-2008/0310484 A1	12-2008	Shattil, Steve J.	375/146
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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